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## Design of a programmable CMOS Charge-Pump for phase-locked loop synthesizers

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### 1. Abstract

A charge pump circuit capable of operating at different switching speed is presented. The switching speed control is added to a typical charge pump circuit by mean of enable switches which allow drive different currents. Charge pump circuit is implemented in AMI 0.5 $\mu$ m CMOS technology. Simulations were performed using Spectre from Cadence<sup>TM</sup>. Simulation results show clearly an increase in the slope of charging or discharging curves of load capacitor during the pumping-up and pumping-down phases.

Keywords: analog electronic design; integrated circuits; charge pump; PLLs; circuit simulation.

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### 2. Introduction

Charge-pump (CP) circuit is a building block of A/D and D/A converters, dynamic random access memory circuits, switched-capacitor circuits and phase locked loop (PLLs). In a PLL system CP circuit consists of two transistor switch which generate up and down current pulses to adjust voltage controlled oscillator (VCO)

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control voltage on filter capacitor. Three important issues of on-chip CP circuits are output voltage ripple, power efficiency and area efficiency [1]. Because large output ripple degrades the performance of the circuit that the CP is powering, for most applications, a low output ripple is desired. CPs with very low power efficiency cancel the benefit of scaling the supply voltage down and are not desirable for portable applications. Area efficiency is desirable for many applications as smaller chip areas are less expensive to fabricate. Among different PLL topologies, charge-pump phase locked loop (CPPLL) is widely used in modern wireless communication systems due to the phase-lock advantages, namely their larger system gain, faster frequency detecting reactions, larger range acquisition and a perfect zero static phase error [2], and also offering programmability features, this last allowing to satisfy the needs set by modern RF reconfigurable systems, able to work under different protocols & standards. An ideal CPPLL model has a perfect zero input phase error, but taking the mismatch into account, certain phase error is introduced in practical circuits. That means the matching precision of CP is directly related to the phase error of the whole PLL system. Non ideal behavior of CP can contribute significantly to PLL output jitter [2, 3] and precision of A/D, D/A converters and switched capacitor filters is affected by the switch-induced error voltage. Non idealities come mainly from charge sharing, charge injection and clock feedthrough in MOS analog switches of CPs, so transistors' switch sizing is a key design variable in order to get best performance of CPs. Different approaches to the reduction of the switch induced error have been proposed in references [4 – 10]. In a PLL system, if phase detector circuit detects change in phase it provides information to CP which converts phase error information into current to generate control voltage of VCO. Up (down) CP current pulses lead to charge (discharge) the filter capacitor. The voltage step during the charge (discharge) is directly related with CP current, then by controlling the magnitude of CP current one could control the charge/discharge speed of filter capacitor and this offers an effective way of enable PLL operation at different frequencies. In this work, a charge-pump topology with two current levels is presented. Design approach of CP circuit is described in section III. In section IV, simulation results will be given. Finally, the conclusion is drawn in section V.

### 3. Charge-pump circuit

A block diagram of a CPPLL synthesizer system is illustrated in Fig. 1. From this figure, one can note five main blocks: phase /frequency detector (PFD), charge-pump (CP), low pass filter (LPF), and voltage controlled oscillator (VCO) and frequency divider. Among them, the CP consists of two switched current sources that pump charge into or out of the LPF according to the output signal from the PFD. I1 is designed as charging current ( $I_{UP}$ ) whereas I2 is identified as a discharging current ( $I_{DW}$ ), and they are nominally equal. Basic operation is as follows: if  $QA = QB = 0$ , S1 and S2 are open and  $V_{ctrl}$  remains constant. If  $QA = 1$  and  $QB = 0$ , then S1 closes whereas S2 is open and  $I_{UP}$  charges the filter capacitor ( $C_p$ ). Conversely, if  $QA = 0$  and  $QB = 1$ , S2 closes and S1 opens, then  $I_{DW}$  discharges  $C_p$ . Thus, if for instance,  $V_{out}$  lags  $V_{in}$ ,  $QA$  continues to produce pulses and  $V_{ctrl}$  rises steadily towards  $VDD$ .

From dynamic behavior of CPPLL the relationship between  $V_{ctrl}$ ,  $I_{UP}$  ( $I_{DW}$ ) and phase difference  $\Delta\phi$  is deduced as follows [11]:

$$V_{ctrl}(t) = \frac{I_{UP}T_{in}}{2\pi C_p} \Delta\phi = \frac{I_{UP}\phi_0}{4\pi f C_p} \tag{1}$$

This means that  $V_{ctrl}$  rises in steps proportional to the ratio  $I_{UP}/C_p$  every period  $T_{in}$  (see Fig. 2). As an example, suppose a 10MHz clock frequency, a  $C_p = 5pF$ , and  $I_{UP} = 10\mu A$ , the resulting voltage step height is 100mV. As Eq. 1 reveals if one doubles  $I_{UP}$ , the slope of  $V_{ctrl}$  vs  $t$  curve should be doubled, that is, the voltage step height now is 200mV. Thus we can

take advantage of this behavior to adjust the speed for charging or discharging filter capacitor [12]. In other words, we can utilize  $I_{UP}$  current as an extra variable control to set up the speed response of the PLL system.

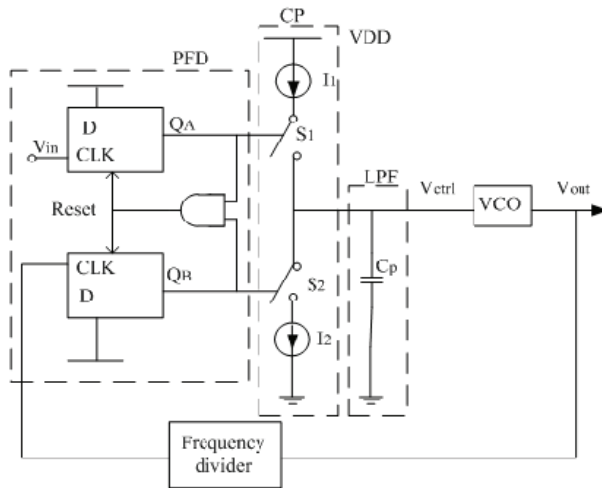


Fig.1: typical CPPLL synthesizer system.

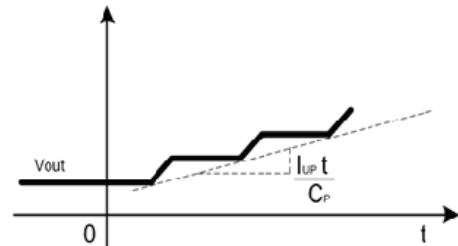


Fig. 2: step response of CPPLL synthesizer.

#### 4. Proposed charge-pump circuit

Conceptual representation of CP circuit in which magnitude currents  $I_{UP}$  ( $I_{DW}$ ) can be adjusted is shown in Fig. 3a. Traditional CP circuit is composed by S1, S2 switch array and transistors MB1, MB2, MB4 MB5, and MB7. MB1 sets  $I_{UP}$  ( $I_{DW}$ ) current through current source composed by MB2, and MB4 (MB5 and MB7). In order to provide CP circuit an option to drive different  $I_{UP}$  ( $I_{DW}$ ) current, enables switches are implemented (Fig. 3b). Basic principle of operation is as follows: when enable signal is applied “enab\_b” switch is closed and transistor MB6 turns-on. If MB6 and MB7 are equally sized  $I_{UP}$  current is doubled and consequently the charge speed of filter capacitor is doubled. This also holds for the complementary part, i. e.,  $I_{DW}$  doubling current when MB3 is turned-on by closing “enab”. The “enable” switch is composed by transistors Me1 and Me2 while Me3 and Me4 forms switch “enab\_b”. Switches S1 and S2 were implemented with transmission gate topology in order to minimize injection current and clockfeedthrough phenomena. The whole circuit is presented in fig. 3b. Transistor MB1, MB2, MB3, MB4 MB5, MB6 and MB7 were sized in order to drive 10uA DC current (Eq. 2) whereas MS1 to MS4 were sized in terms of 1kΩ of on-resistance switches (Eq. 3). Me1 to Me4 transistors were sized to set a  $V_G$  voltage of MB6 (MB3) 100mV higher than  $V_{TH}$ . Process parameters i. e.,  $V_{TH}$ , KP,  $\lambda$ , etc., were extracted by Spectre simulations using AMI C5N technology. Table 1 summarizes the transistor dimensions of CP circuit shown in Fig. 3. Notice the reduced number of transistors as well as their small dimensions implies low area in layout.

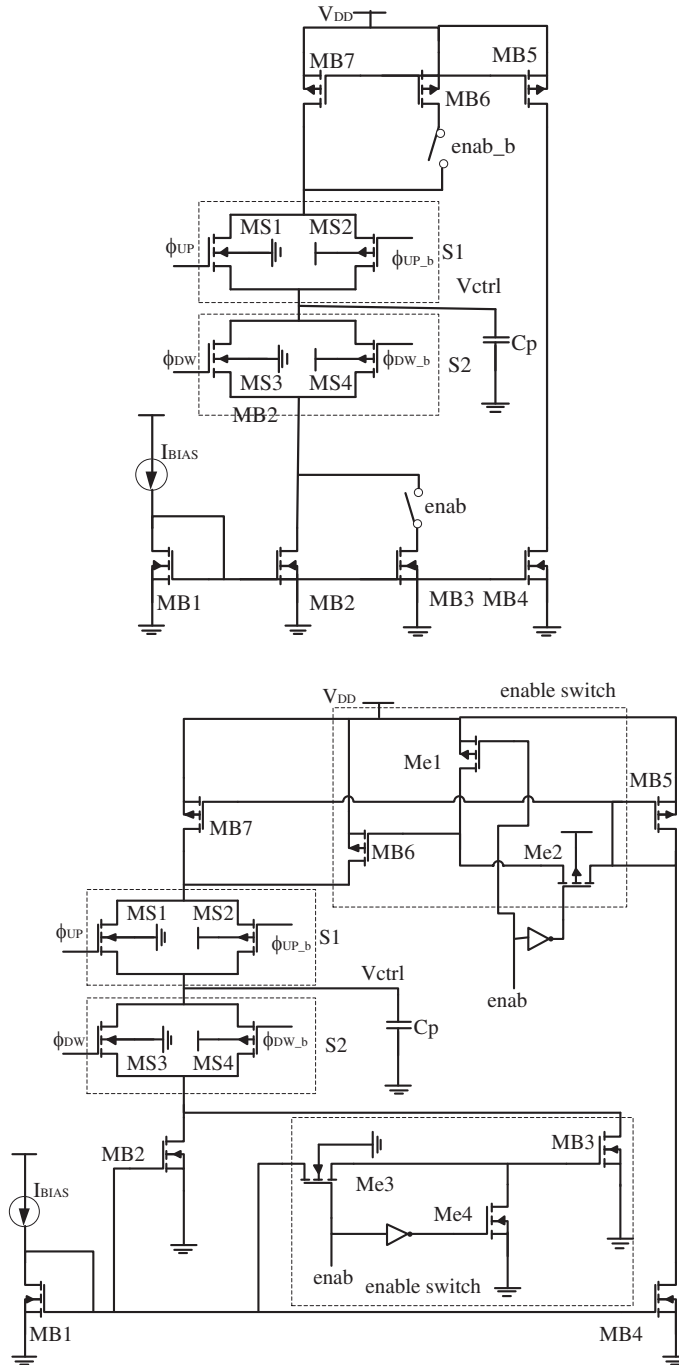


Fig.3: (a) Conceptual representation of CP circuit for driving different  $I_{UP}$  ( $I_{DW}$ ) currents, (b) Final charge pump schematic approach.

$$I_D = \frac{1}{2}kP\frac{W}{L}(V_{GS} - V_{TH})^2 \tag{2}$$

$$R_{ON} = \frac{1}{kP\frac{W}{L}(V_{GS} - V_{TH})} \tag{3}$$

Table 1: Charge Pump circuit parameter

Block	Transistor	W (um)	L (um)
Bias	MB1, MB2, MB3,	2.1 <sub>MB1,2,3,4</sub>	1.2
	MB4, MB5, MB6, MB7	3.3 <sub>MB5,6,7</sub>	
S1 switch	MS1, MS2	1.5	0.6
S2 switch	MS3, MS4	1.65	0.6
I <sub>UP</sub> enable switch	Me1, Me2,	1.5	0.6
I <sub>DW</sub> enable switch	Me3, Me4,	1.5	0.6

5. Simulation results

Transient simulations have been performed using a 0.5µm CMOS process from AMI C5N technology provided by MOSIS and Spectre simulator provided by Cadence™. Fig. 4a presents a closed up image during the pumping-up phase for the two I<sub>UP</sub> current levels. As can be noticed from Fig. 4a, the step sizes of Vctrl are quite matched with model given by Eq. 1, that is, step size doubles when I<sub>UP</sub> is doubled. Similar behavior was observed during the pumping-down phase (Fig. 4b). Also a higher slope can be observed for the charge intervals in the whole pumping up or pumping down phase (Fig. 5) which validates this approach.

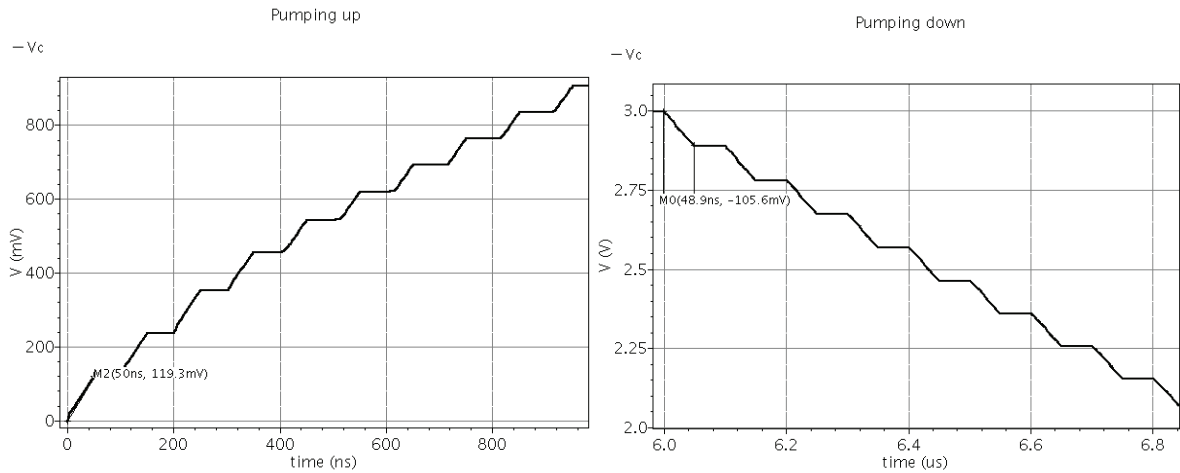


Fig. 4: Simulation results of proposed charge pump circuit (VDD = 3V, f= 10MHz): (a) Pumping-up, (b) pumping down.

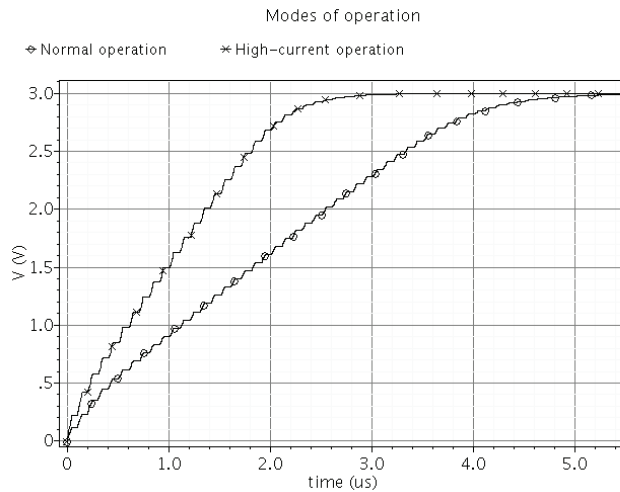


Fig.5: Charge pump simulation results.

## 6. Conclusions

This paper proposed a new structure of high performance CMOS charge pump for phase-locked loop synthesizer. According to the test results, with the help of enable switch added to the traditional charge pump circuit  $I_{UP}$  ( $I_{DW}$ ) current can be chosen to fix the charge/discharge speed of filter capacitor. The proposed CP has a wide current match range, a high matching precision. This CMOS charge pump structure can be applied in a CPPLL with high performance.

## References

- [1] Ryan Perigny, Un-Ku Moon and Gabor Temes, Area efficient CMOS charge pump circuits, in proc. ISCAS2001, May 6 – 9 2001, Sidney Australia.
- [2] Li Zhiquan, Zheng Shuangshuang, and Hou Ningbing, Design of a high performance CMOS charge pump for phase-locked loop synthesizers, Journal of Semiconductors, Vol. 32, No. 7, pp 075007-1 - 075007-5, July 2011.
- [3] Jianbin Pan, Yuanfu Zhao, Design of a Charge-Pump PLL for LVDS SerDes, in proc. IMECS2010, March 17 – 19, 2010, Hong Kong
- [4] C.M. Hung and K. K. O, "A fully integrated 1.5V, 5.5 GHz CMOS phase-locked loop," IEEE J. Solid-State Circuits, vol.37, pp. 521–525, 2002.
- [5] M. Tiebout, "Low-power, low-phase noise differentially tuned quadrature VCO design in standard CMOS," IEEE J. Solid- State Circuits, vol. 36, pp. 1018–1024, 2001.
- [6] M. Szelemiak, et al, "Small-Scale Readout System Prototype for the STAR PIXEL Detector", in Proc. IEEE NSS '07, vol. 2, pp. 1474-1481, Nov, 2007.
- [7] C. -H Lee, Kelly McClellan, and I. Choma, Supply noise insensitive CMOS PLL with a voltage regulator using DC-DC capacitive converter," IEEE J. Solid-State Circuits, vol. 36, Oct. 2001, pp. 1453-1463.
- [8] L. Lacaita, S. Levatino, and C. Samon, "Integrated Frequency Synthesizers for Wireless Systems," Cambridge University Press, 2007.
- [9] H. M. Chien, T. H. Lin, B. Ibrahim, L. Zhang, M. Rofougaran, A. Rofougaran, and W. J. Kaiser, "A 4 GHz fractional-N synthesizer for IEEE 802.11a," in Proc. IEEE Symp. VLSI Circuits, Jun. 2004, pp.46–49.
- [10] J. Dickson, "On-chip high-voltage generation in MOS integrated circuits using an improved voltage multiplier technique," IEEE Journal of Solid-State Circuits, vol. SC-11, pp. 374-378, June 1976.
- [11] B. Razavi, Design of analog CMOS integrated circuits McGrawHill 2001.
- [12] Esdras Juarez-Hernández, and Alejandro Díaz Sánchez, A Novel CMOS Charge-Pump Circuit with Positive Feedback for PLL Applications. The 8th IEEE International Conference on Electronics, Circuits and Systems, ICECS, vol.1, pp: 349 – 352, September 2001.